R10000 Superscalar Microprocessor

Ali Ahi, Yung-chin Chen, Robert Conrad, Randal Martin, Ratan Ramchandani, Mahdi Seddighnezhad, Greg Shippen, Hong-men Su, Hector Sucar, Nader Vasseghi, William Voegtli Jr., Kenneth Yeager, Yeffi

Presentation Outline

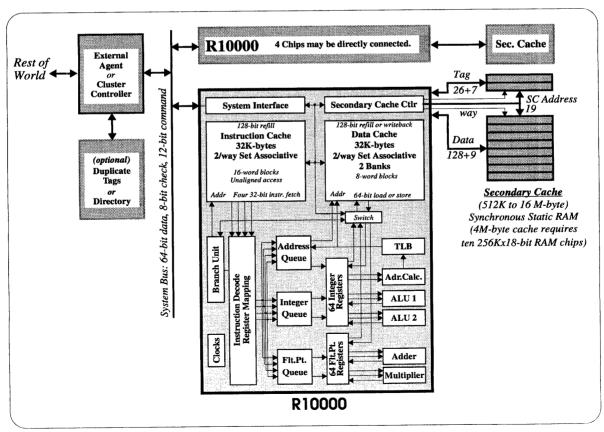
- Architecture of CPU and FPU
- Memory Hierarchy
- System Configuration
- Verification and Design Methods

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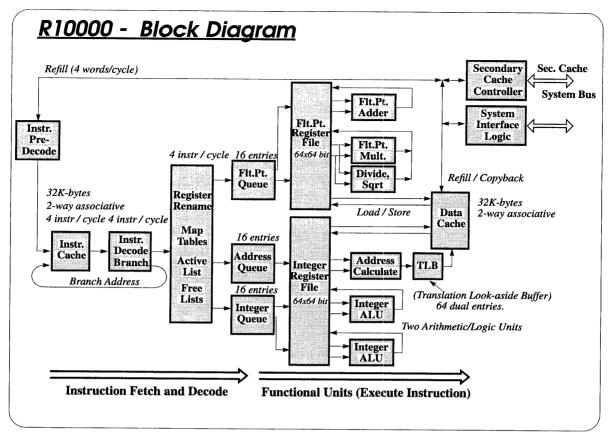


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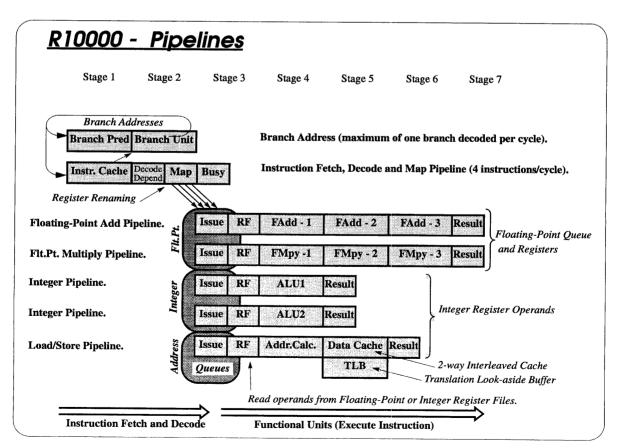
SiliconGraphics
Computer Systems



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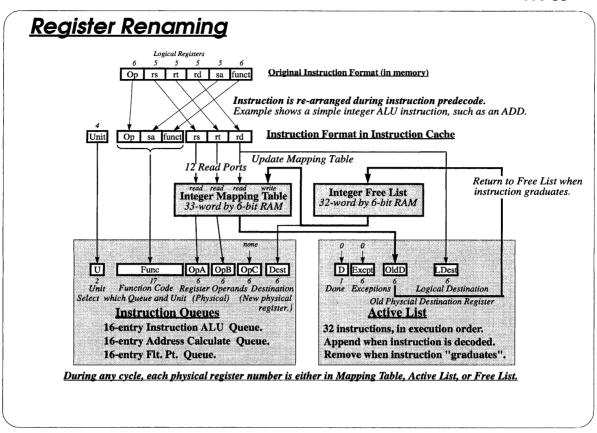


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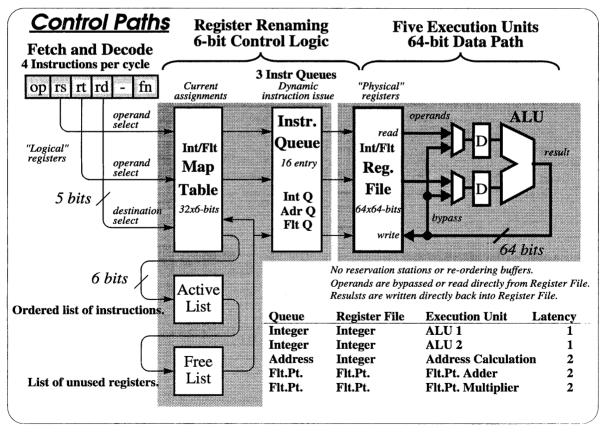




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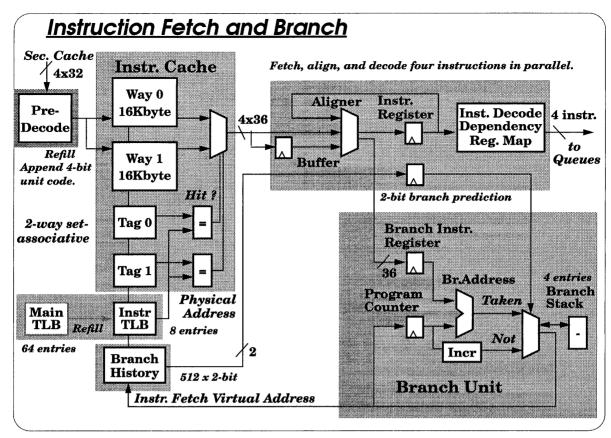


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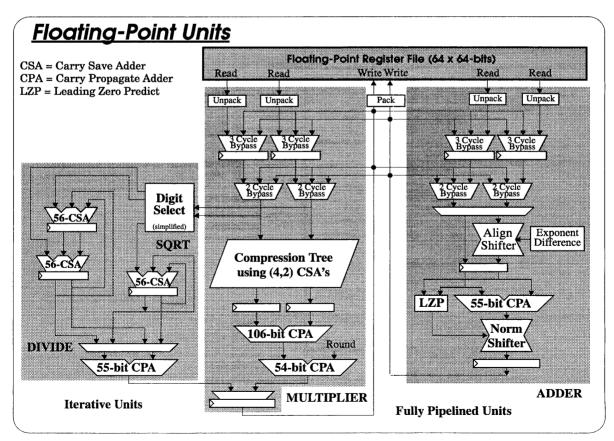
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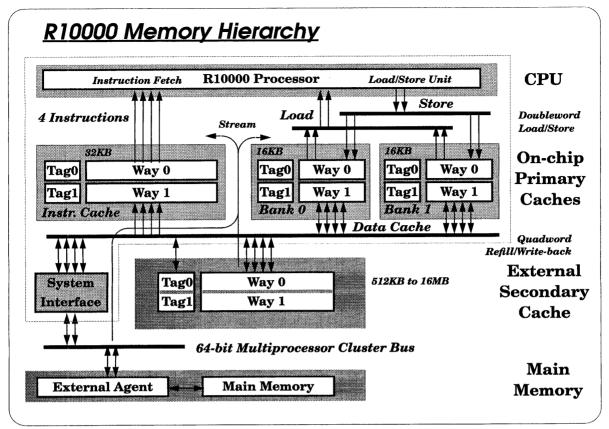


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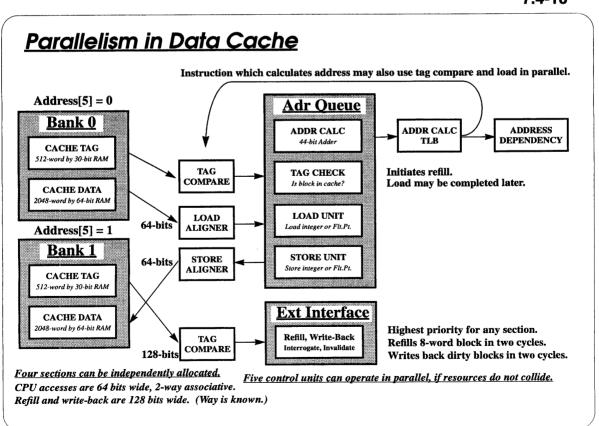




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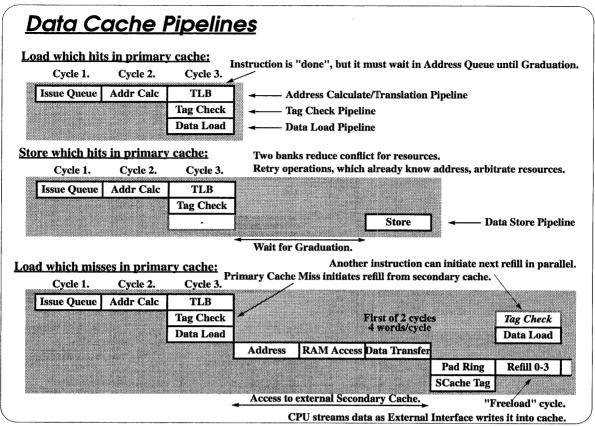


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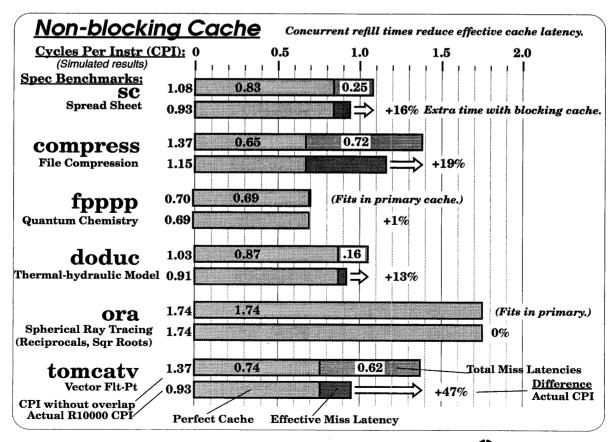
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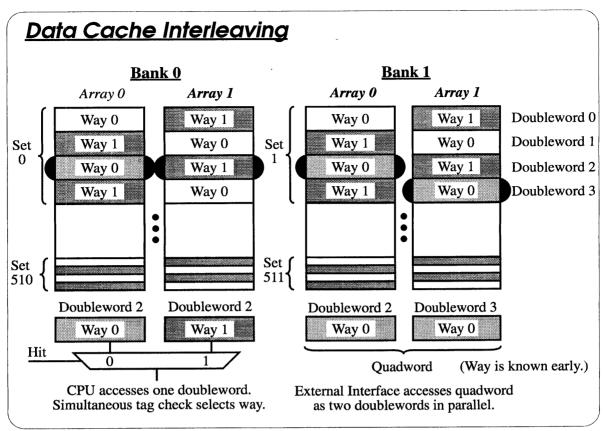


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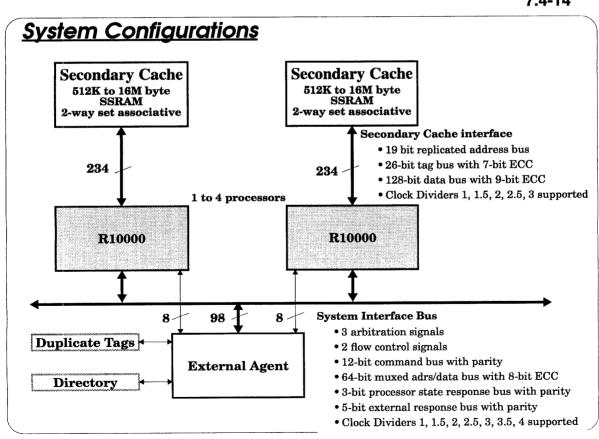




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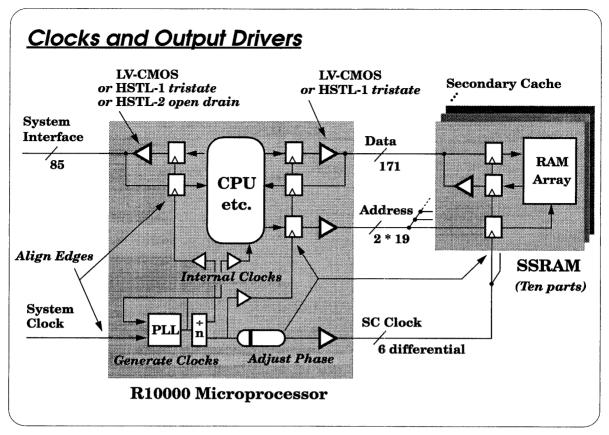


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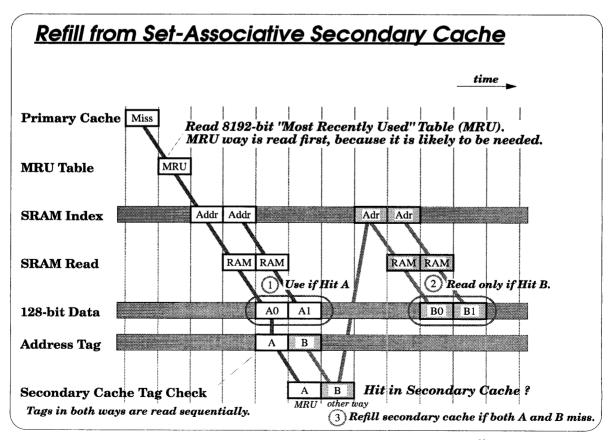
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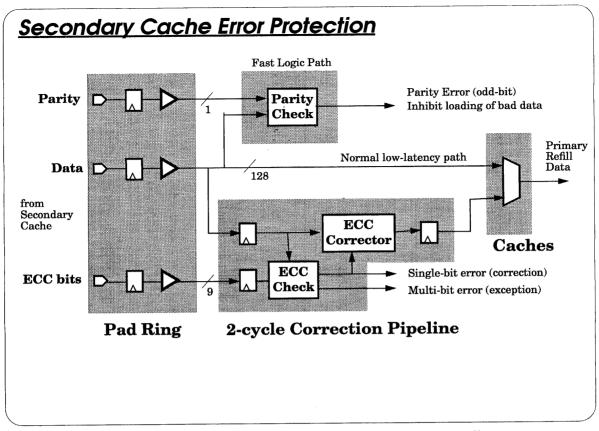


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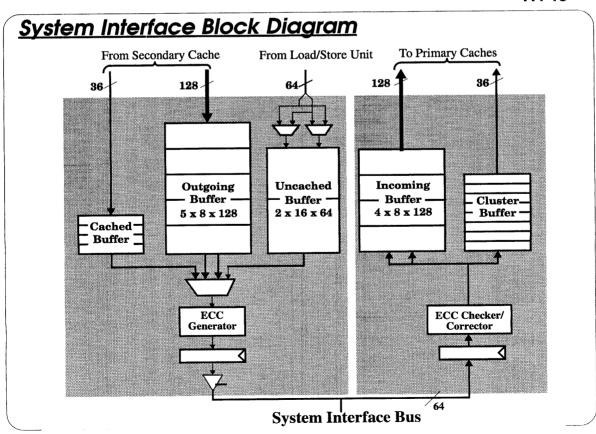




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Functional Verification Methodology

- **■** Tools and environment:
 - Inhouse HDL and simulator with backup and replay.
 - Graphical user interface for simulation and regression.
 - An instruction level simulator as a reference machine, which checks
 - Architecture registers
 - **■** Memory hierarchy
 - Programmable random code generators for UP and MP.
 - Arc coverage and consistency checking for state machines.
- **■** C-based System Model supports
 - Secondary cache array, memory controller and array, bus controller.
 - Bus protocol checking.
 - **■** External events:
 - programmable or purely random
 - imbeded in diagnostics for fine-grain control
 - 1 to 4 processor configuration.

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Diagnostic Development

- **■** Directed Diagnostics
 - Architecture Verification Programs (AVP)
 - Microarchitecture Verification Programs (MVP)
 - Implementation Verification Programs (IVP)
- Random Diagnostics From Programmable Random Code Generators
 - **■** Functional unit intensive
 - Load/Store intensive
 - **■** Branch intensive
 - Mix of the above under UP and MP environments
- Diags are self-checking and/or compared with the reference machine.
- UP and MP applications.
- Booting O/S's on R10000 RTL: 2 Unix O/S's and NT.



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Test Features

ExtInt & Caches EIC CPU FPU

Tests Cost
EIC
CPU
FPU

- On-chip virtual output pins:
 - Physical design partitioning
 Direct observability of internal signals
 Signature compression through LFSRs
 (Linear-Feedback Shift Register)
- Dedicated test structures:

No performance impact No logic design overhead No special clock requirements

■ Enhanced debug and diagnostics:

Cycle-by-cycle sampling of internal signals Observed signals correlate to logic specification Signature analysis

■ Test cost reduction:

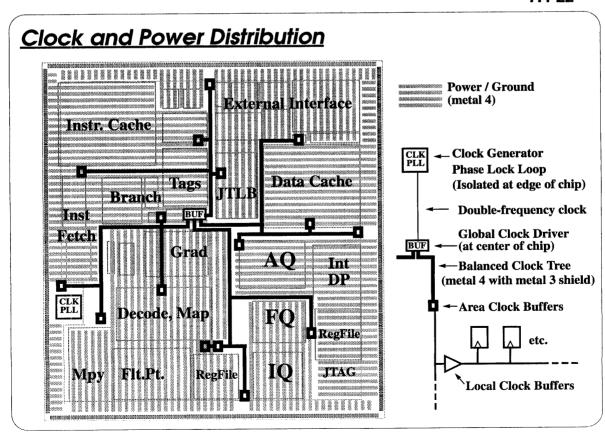
No special ATE requirements Internal test-output compression by signature Test and fault partitioning. Reduced test time and higher fault coverage

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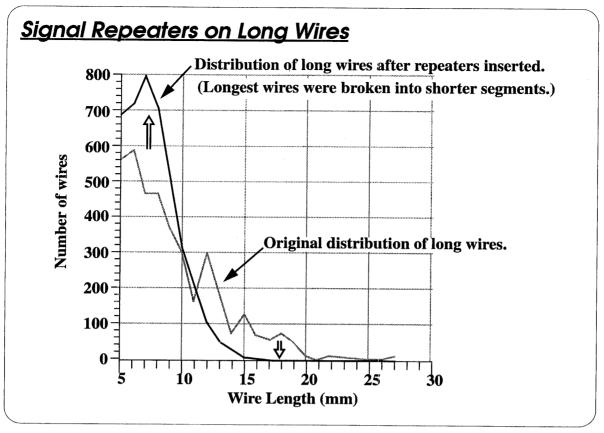
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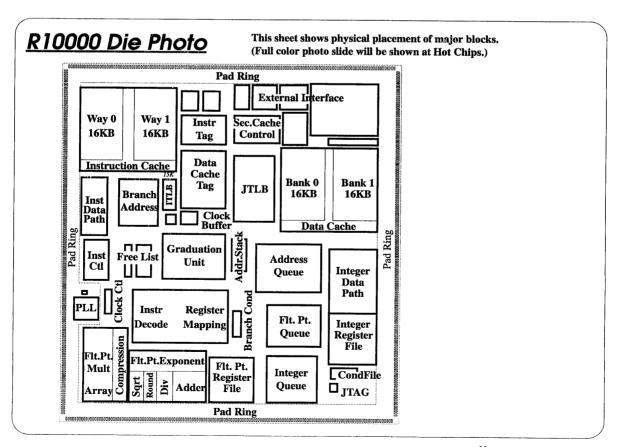
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